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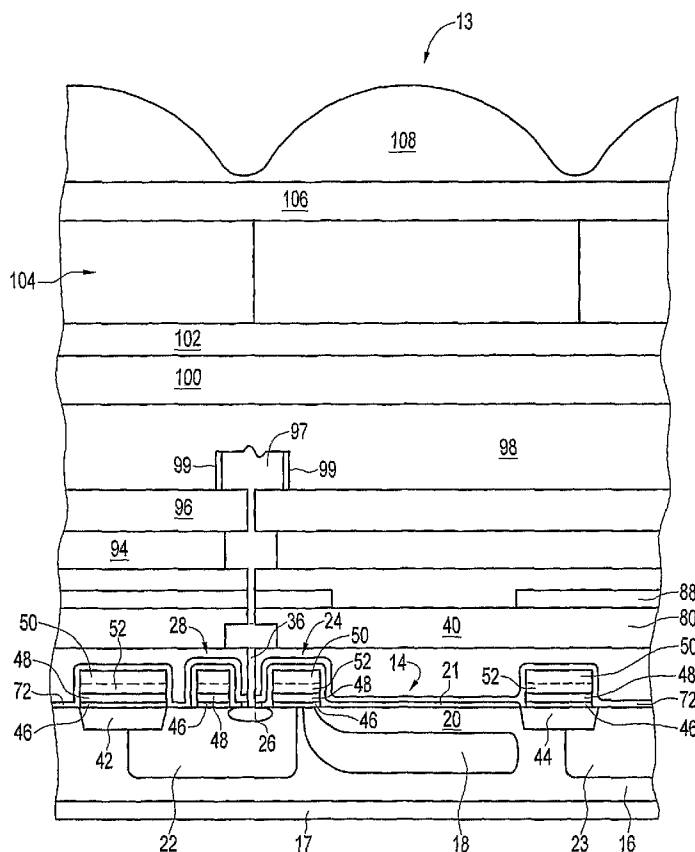
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- (71) Applicant (for all designated States except US): **MICRON TECHNOLOGY, INC.** [US/US]; 8000 S. Federal Way, Boise, ID 83707-0006 (US).
- (72) Inventor; and
- (75) Inventor/Applicant (for US only): **LI, Jiutao** [CN/US]; 5325 E. Branchwood Drive, Boise, ID 83716 (US).
- (74) Agent: **D'AMICO, Thomas, J.**; Dickstein Shapiro LLP, 1825 Eye Street, NW, Washington, DC 20006-5403 (US).

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(54) Title: SOLID-STATE IMAGER AND FORMATION METHOD USING ANTI-REFLECTIVE FILM FOR OPTICAL CROSSTALK REDUCTION



(57) Abstract: Conductive lines in an imaging device are coated with an anti-reflective film to reduce crosstalk caused by light reflecting from the conductive lines. An interface results between the anti-reflective film and the surface of the conductive line surface. A second interface exists between the anti-reflective film and an overlying insulating layer. The anti-reflective film is formed from a material having a complex refractive index such that reflectance is reduced at each of the two interfaces. The anti-reflective film also can be light absorbing to provide further reductions in light reflection and consequent crosstalk.

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